

DYNAMIC CHARACTERISTICS

APT40GR120B2D30

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
C_{ies}	Input Capacitance	Capacitance $V_{GE} = 0V, V_{CE} = 25V$ $f = 1MHz$		3980		pF
C_{oes}	Output Capacitance			320		
C_{res}	Reverse Transfer Capacitance			80		
V_{GEP}	Gate to Emitter Plateau Voltage	Gate Charge $V_{GE} = 15V$ $V_{CE} = 600V$ $I_C = 40A$		7		V
$Q_g^{(3)}$	Total Gate Charge			210		nC
Q_{ge}	Gate-Emitter Charge			25		
Q_{gc}	Gate- Collector Charge			90		
$t_{d(on)}$	Turn-On Delay Time	Inductive Switching (25°C) $V_{CC} = 600V$ $V_{GE} = 15V$ $I_C = 40A$ $R_G = 4.3 \Omega^{(4)}$ $T_J = +25^\circ C$		22		ns
t_r	Current Rise Time			25		
$t_{d(off)}$	Turn-Off Delay Time			163		
t_f	Current Fall Time			40		
$E_{on2}^{(5)}$	Turn-On Switching Energy			1375	3000	μJ
$E_{off}^{(6)}$	Turn-Off Switching Energy			906	1650	
$t_{d(on)}$	Turn-On Delay Time	Inductive Switching (125°C) $V_{CC} = 600V$ $V_{GE} = 15V$ $I_C = 40A$ $R_G = 4.3 \Omega^{(4)}$ $T_J = +125^\circ C$		22		ns
t_r	Current Rise Time			25		
$t_{d(off)}$	Turn-Off Delay Time			185		
t_f	Current Fall Time			47		
$E_{on2}^{(5)}$	Turn-On Switching Energy			1916	3500	μJ
$E_{off}^{(6)}$	Turn-Off Switching Energy			1186	2500	

THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	Min	Typ	Max	Unit
$R_{\theta JC}$	Junction to Case Thermal Resistance (IGBT)			.25	°C/W
	Junction to Case Thermal Resistance (Diode)			.80	
$R_{\theta JA}$	Junction to Ambient Thermal Resistance			40	
W_T	Package Weight		.22		oz
			6.2		g

1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

2 Pulse test: Pulse Width < 380μs, duty cycle < 2%.

3 See Mil-Std-750 Method 3471.

4 R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

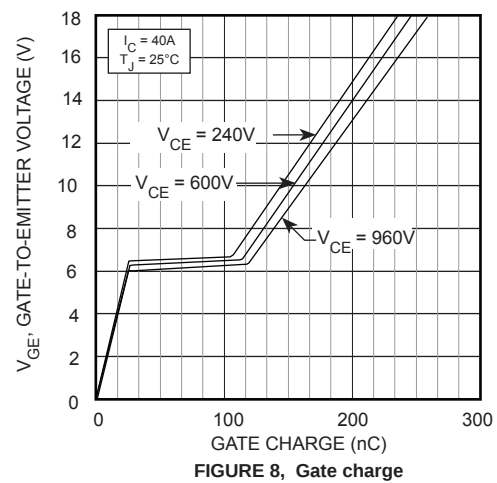
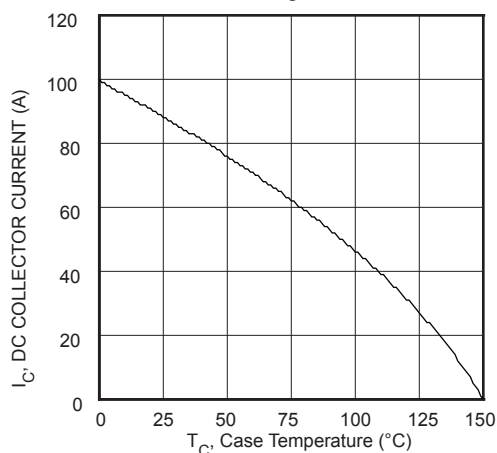
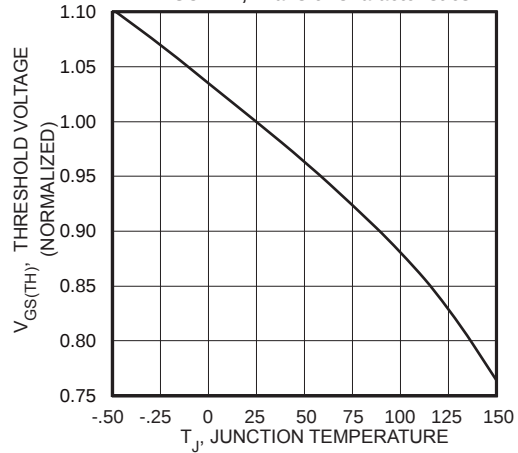
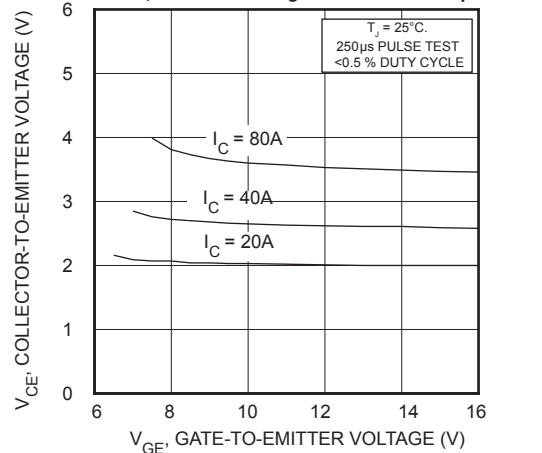
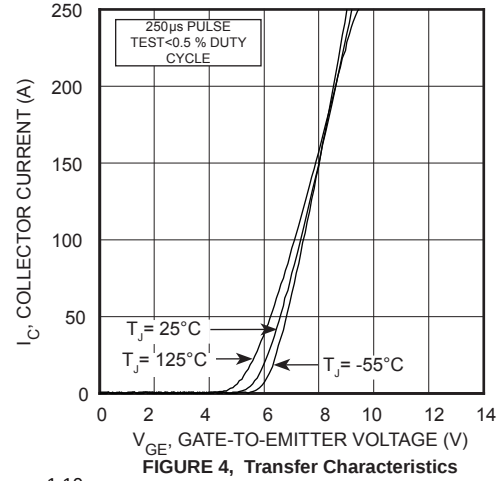
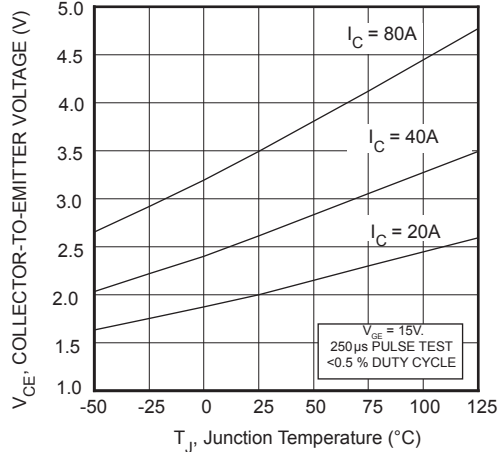
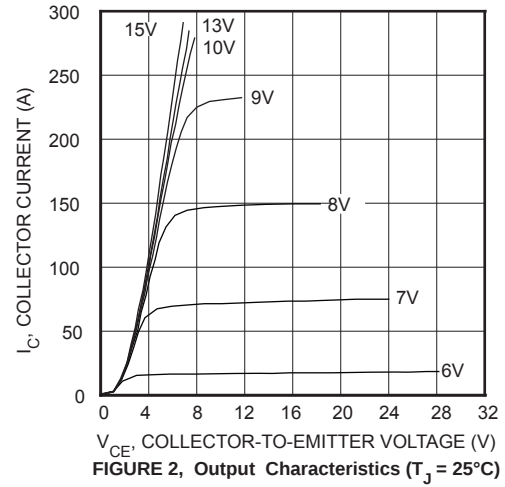
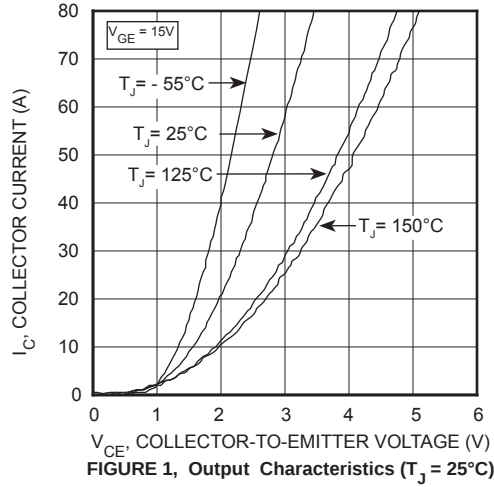
5 E_{on2} is the clamped inductive turn on energy that includes a commutating diode reverse recovery current in the IGBT turn on energy loss. A combi device is used for the clamping diode.

6 E_{off} is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1.

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

TYPICAL PERFORMANCE CURVES

APT40GR120B2D30



TYPICAL PERFORMANCE CURVES

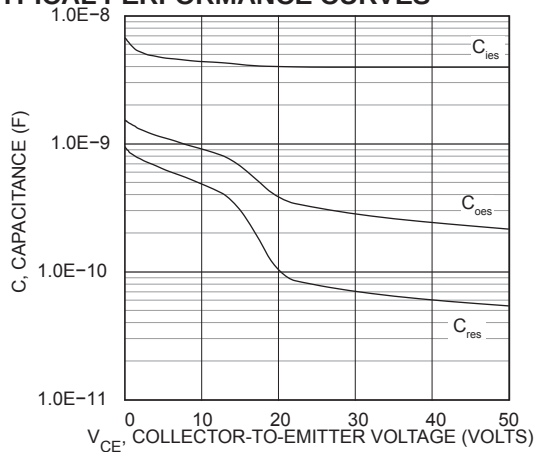


FIGURE 9, Capacitance vs Collector-To-Emitter Voltage

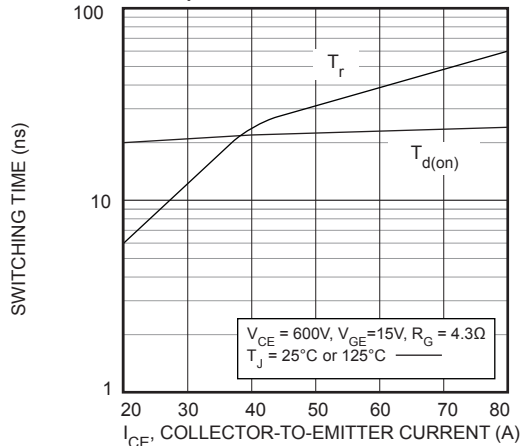


FIGURE 11, Turn-On Time vs Collector Current

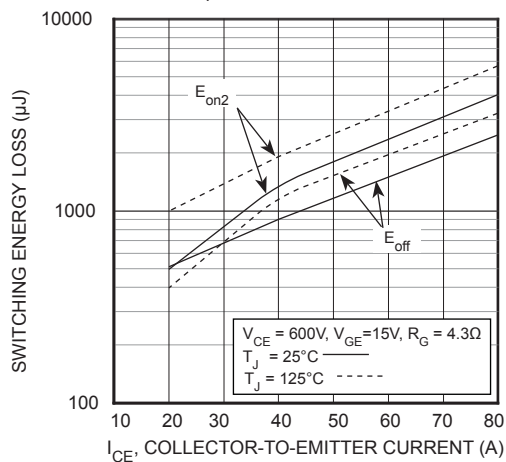


FIGURE 13, Energy Loss vs Collector Current

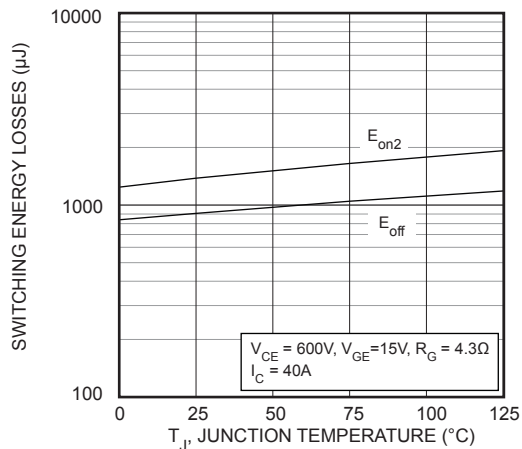


FIGURE 15, Energy Losses vs Junction Temperature

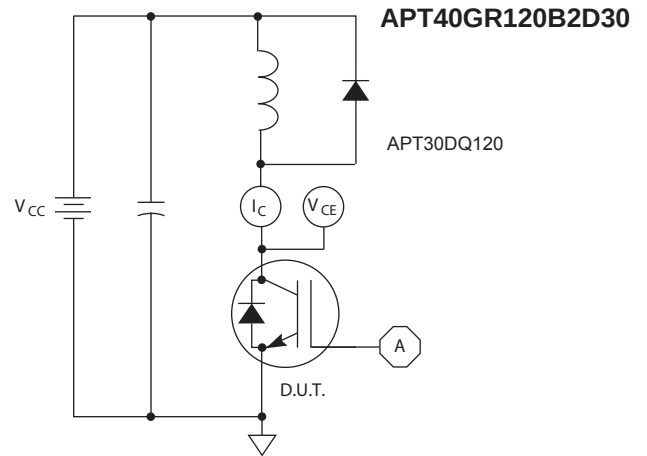


FIGURE 10, Inductive Switching Test Circuit

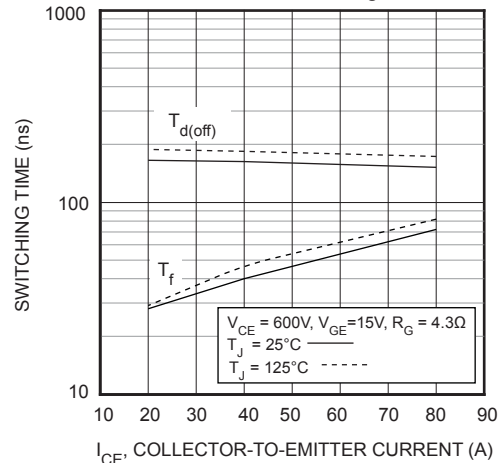


FIGURE 12, Turn-Off Time vs Collector Current

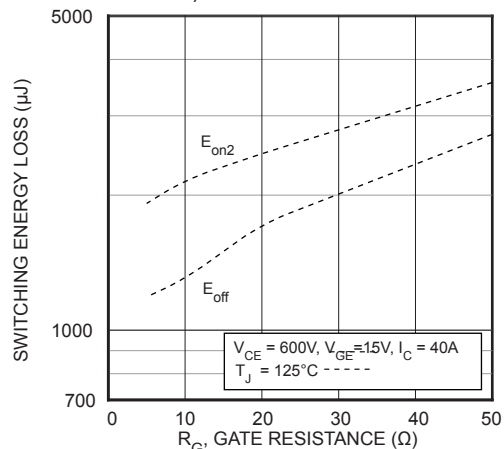


FIGURE 14, Energy Loss vs Gate Resistance

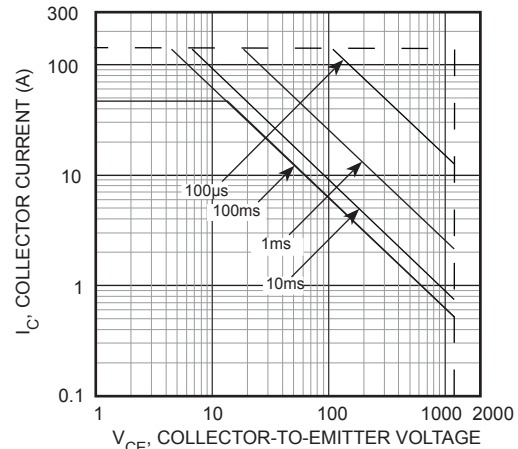
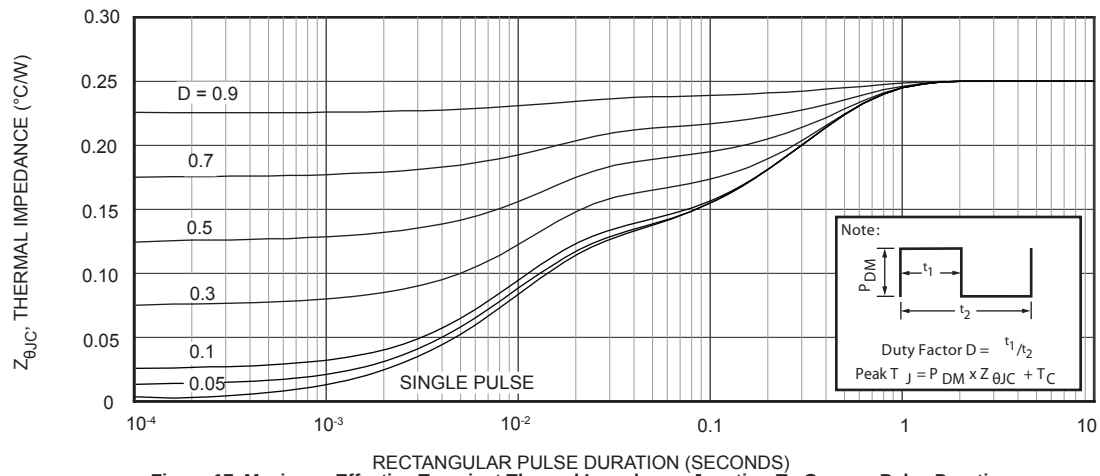


FIGURE 16, Minimum Switching Safe Operating Area



ULTRAFAST SOFT RECOVERY ANTI-PARALLEL DIODE

MAXIMUM RATINGS

All Ratings: $T_C = 25^\circ\text{C}$ unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT40GR120B2D30			UNIT
$I_{F(AV)}$	Maximum Average Forward Current ($T_C = 110^\circ\text{C}$, Duty Cycle = 0.5)		30		Amps
$I_{F(RMS)}$	RMS Forward Current (Square wave, 50% duty)		43		
I_{FSM}	Non-Repetitive Forward Surge Current ($T_J = 45^\circ\text{C}$, 8.3ms)		210		

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions		MIN	TYP	MAX	UNIT
V_F	Forward Voltage	$I_F = 30\text{A}$		2.8		Volts
		$I_F = 60\text{A}$		3.4		
		$I_F = 30\text{A}$, $T_J = 125^\circ\text{C}$		2.1		

DYNAMIC CHARACTERISTICS

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
t_{rr}	Reverse Recovery Time	$I_F = 1\text{A}$, $di_F/dt = -100\text{A}/\mu\text{s}$, $V_R = 30\text{V}$, $T_J = 25^\circ\text{C}$	-	26		ns
t_{rr}	Reverse Recovery Time	$I_F = 30\text{A}$, $di_F/dt = -200\text{A}/\mu\text{s}$ $V_R = 800\text{V}$, $T_C = 25^\circ\text{C}$	-	320		
Q_{rr}	Reverse Recovery Charge		-	545		nC
I_{RRM}	Maximum Reverse Recovery Current		-	4	-	Amps
t_{rr}	Reverse Recovery Time	$I_F = 30\text{A}$, $di_F/dt = -200\text{A}/\mu\text{s}$ $V_R = 800\text{V}$, $T_C = 125^\circ\text{C}$	-	435		ns
Q_{rr}	Reverse Recovery Charge		-	2100		nC
I_{RRM}	Maximum Reverse Recovery Current		-	9	-	Amps
t_{rr}	Reverse Recovery Time	$I_F = 30\text{A}$, $di_F/dt = -1000\text{A}/\mu\text{s}$ $V_R = 800\text{V}$, $T_C = 125^\circ\text{C}$	-	180		ns
Q_{rr}	Reverse Recovery Charge		-	2975		nC
I_{RRM}	Maximum Reverse Recovery Current		-	28		Amps

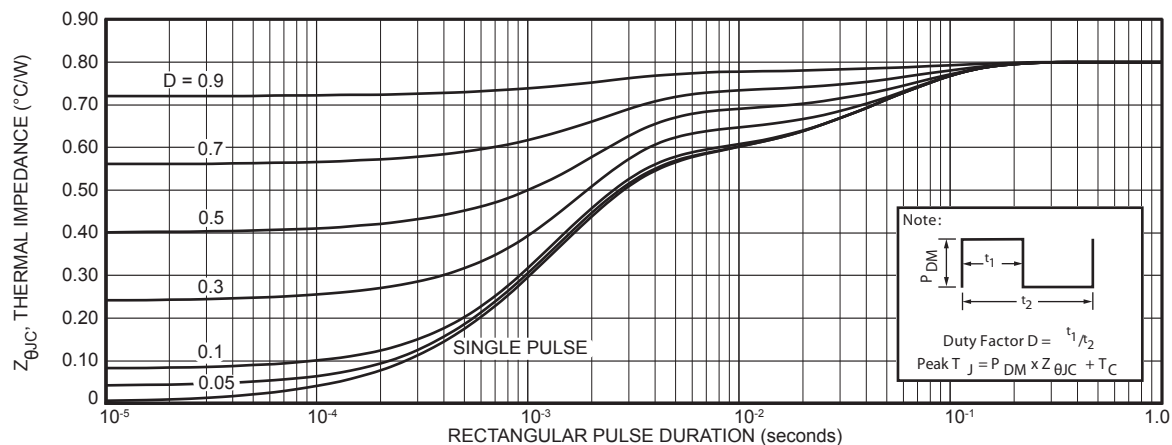


FIGURE 18. MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs. PULSE DURATION

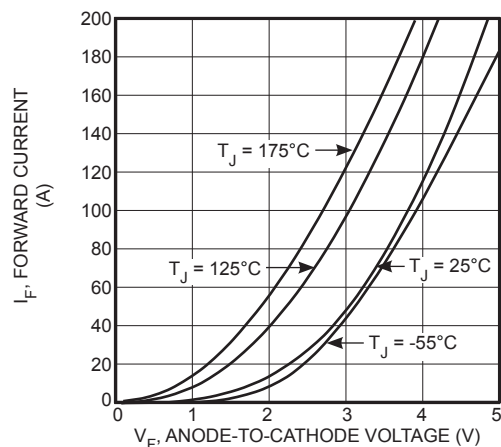


Figure 19. Forward Current vs. Forward Voltage

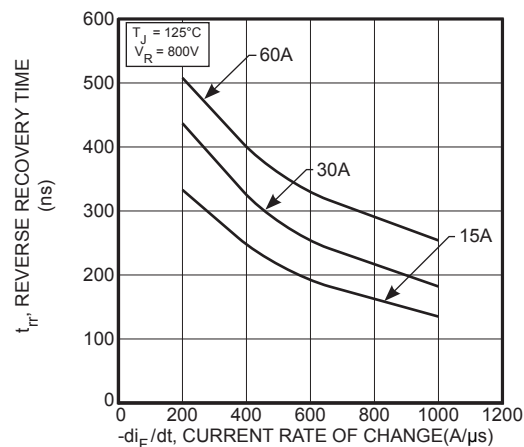


Figure 20. Reverse Recovery Time vs. Current Rate of Change

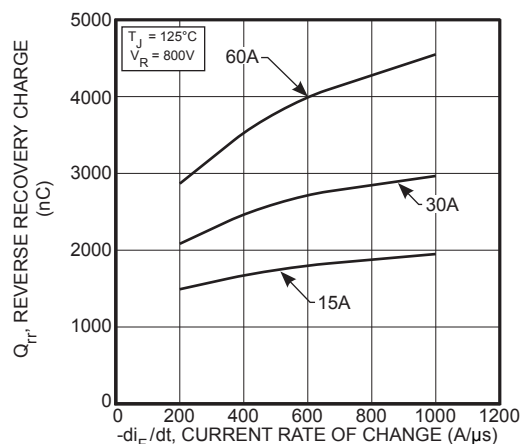


Figure 21. Reverse Recovery Charge vs. Current Rate of Change

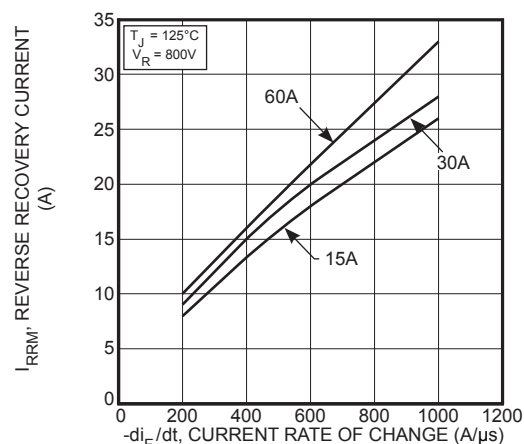


Figure 22. Reverse Recovery Current vs. Current Rate of Change

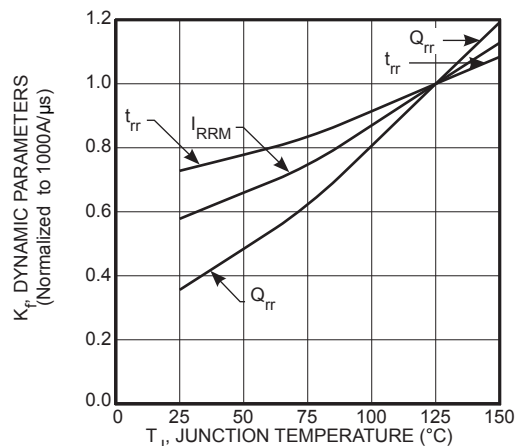


Figure 23. Dynamic Parameters vs. Junction Temperature

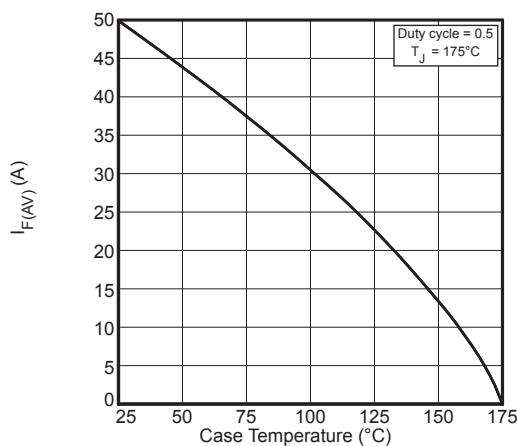


Figure 24. Maximum Average Forward Current vs. Case Temperature

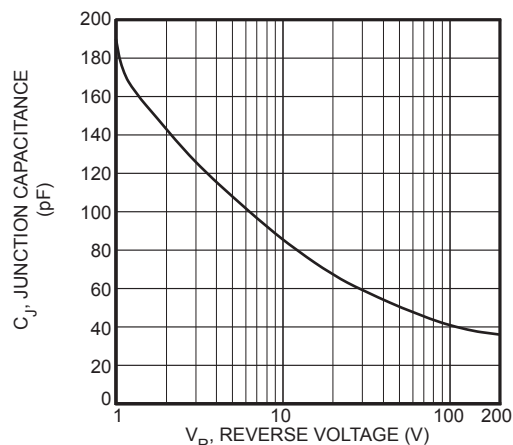


Figure 25. Junction Capacitance vs. Reverse Voltage

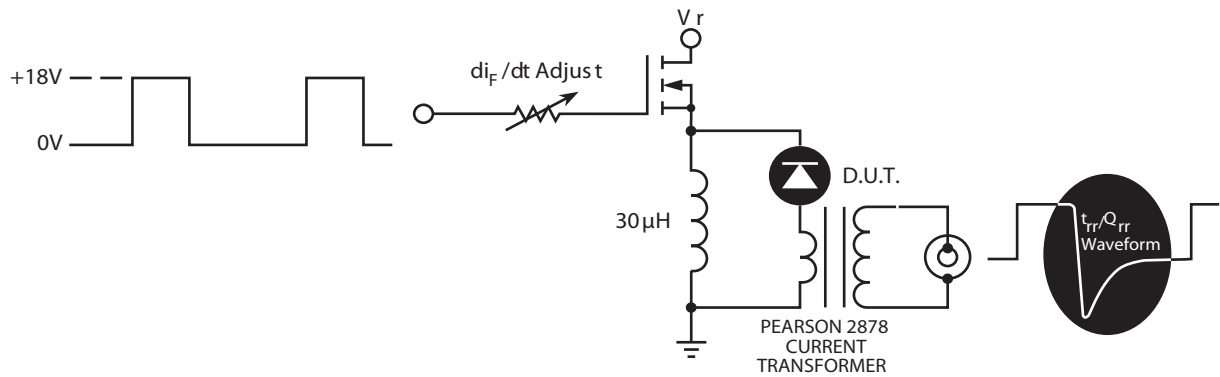


Figure 26. Diode Test Circuit

- 1 I_F - Forward Conduction Current
- 2 di_F/dt - Rate of Diode Current Change Through Zero Crossing.
- 3 I_{RRM} - Maximum Reverse Recovery Current
- 4 t_{rr} - Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and $0.25 I_{RRM}$ passes through zero.
- 5 Q_{rr} - Area Under the Curve Defined by I_{RRM} and t_{rr} .

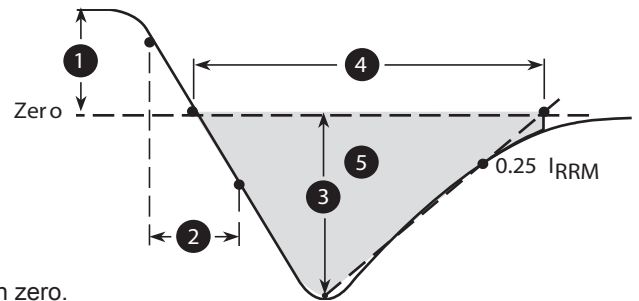
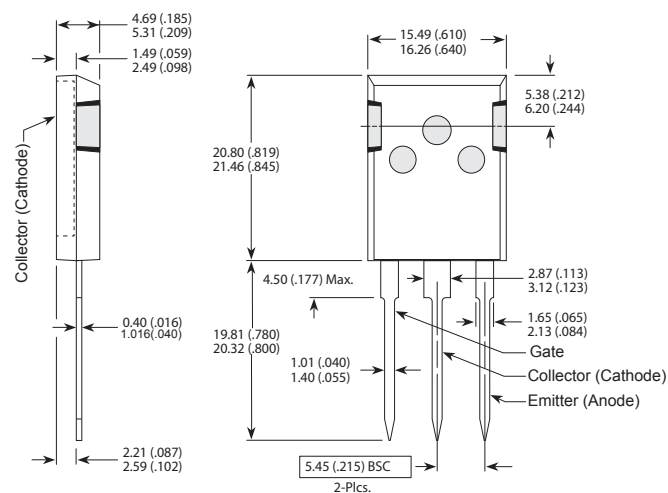


Figure 27. Diode Reverse Recovery Waveform Definition

T-MAX[®] (B2) Package Outline

These dimensions are equal to the TO-247 without the mounting hole.

Dimensions in Millimeters and (Inches)